

INTERNATIONAL SEARCH REPORT

International Application No

PCT/G5 03/04429

A. CLASSIFICATION OF SUBJECT MATTER
IPC 7 G01R31/26

According to International Patent Classification (IPC) or to both national classification and IPC

B. FIELDS SEARCHED

Minimum documentation searched (classification system followed by classification symbols)

IPC 7 G01R

Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched

Electronic data base consulted during the international search (name of data base and, where practical, search terms used)

INSPEC, EPO-Internal

C. DOCUMENTS CONSIDERED TO BE RELEVANT

Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X	PLATZKER A ET AL: "Characterization of GaAs devices by a versatile pulsed I-V measurement system" MICROWAVE SYMPOSIUM DIGEST, 8 May 1990 (1990-05-08), pages 1137-1140, XP010004518	1-4,6, 11,14-17
Y	*The whole document*	5
X	EP 0 800 091 A (MITSUBISHI ELECTRIC CORP) 8 October 1997 (1997-10-08)	1,3,14, 15
Y	column 2, line 19 - column 3 line 10; column 19, line 53 -column 21, line 45; figures 22,27	5
	--- -/--	

☒ Further documents are listed in the continuation of box C.☒ Patent family members are listed in annex.

* Special categories of cited documents:

- *A* document defining the general state of the art which is not considered to be of particular relevance
- *E* earlier document but published on or after the international filing date
- *L* document which may throw doubts on priority claim(s) or which is cited to establish the publication date of another citation or other special reason (as specified)
- *O* document referring to an oral disclosure, use, exhibition or other means
- *P* document published prior to the international filing date but later than the priority date claimed

- *T* later document published after the international filing date or priority date and not in conflict with the application but cited to understand the principle or theory underlying the invention
- *X* document of particular relevance; the claimed invention cannot be considered novel or cannot be considered to involve an inventive step when the document is taken alone
- *Y* document of particular relevance; the claimed invention cannot be considered to involve an inventive step when the document is combined with one or more other such documents, such combination being obvious to a person skilled in the art.
- * & * document member of the same patent family

Date of the actual completion of the international search

8 March 2004

Date of mailing of the international search report

17/03/2004

Name and mailing address of the ISA

European Patent Office, P.B. 5818 Patentlaan 2
NL - 2280 HV Rijswijk
Tel. (+31-70) 340-2040, Tx. 31 651 epo nl,
Fax: (+31-70) 340-3016

Authorized officer

Meggyesi, Z

INTERNATIONAL SEARCH REPORT

International Application No

PCT/GB 03/04429

C.(Continuation) DOCUMENTS CONSIDERED TO BE RELEVANT

Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X	FUJII K: "An improved GaAs MESFET model for the pulsed I-V measurement" MICROWAVE SYMPOSIUM DIGEST, 1995., IEEE MTT-S INTERNATIONAL ORLANDO, FL, USA 16-20 MAY 1995, NEW YORK, NY, USA, IEEE, US, 16 May 1995 (1995-05-16), pages 615-618, XP010612290 ISBN: 0-7803-2581-8	1, 14
A	*The whole document*	2-13, 15-18
X	----- BARTON T M: "NARROW PULSE MEASUREMENT OF DRAIN CHARACTERISTICS OF GAAS MESFETS" ELECTRONICS LETTERS, IEE STEVENAGE, GB, vol. 23, no. 13, 18 June 1987 (1987-06-18), pages 686-687, XP002057571 ISSN: 0013-5194 *The whole document* -----	1, 2, 14

INTERNATIONAL SEARCH REPORT

International Application No

PCT/GB 03/04429

Patent document cited in search report		Publication date		Patent family member(s)	Publication date
EP 0800091	A	08-10-1997	JP	9274064 A	21-10-1997
			EP	0800091 A2	08-10-1997
			US	5905384 A	18-05-1999
<hr/>					